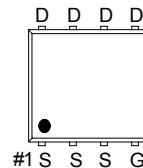
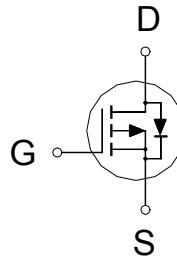


NIKO-SEM
**P-Channel Logic Level Enhancement Mode
Field Effect Transistor**
PE521BA
PDFN 3x3P
Halogen-Free & Lead-Free
PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
-20V	20mΩ	-23A


G : GATE
D : DRAIN
S : SOURCE
ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	-20	V
Gate-Source Voltage	V_{GS}	± 8	V
Continuous Drain Current ³	I_D	-23	A
		-18	
		-7	
		-6	
Pulsed Drain Current ¹	I_{DM}	-60	
Avalanche Current	I_{AS}	-20	
Avalanche Energy	E_{AS}	20	mJ
Power Dissipation	P_D	17.8	W
		11.4	
		1.8	
		1.2	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	$R_{\theta JA}$		68	
Junction-to-Case	$R_{\theta JC}$		7	°C / W

¹Pulse width limited by maximum junction temperature.

²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

³Package limitation current is -11A.

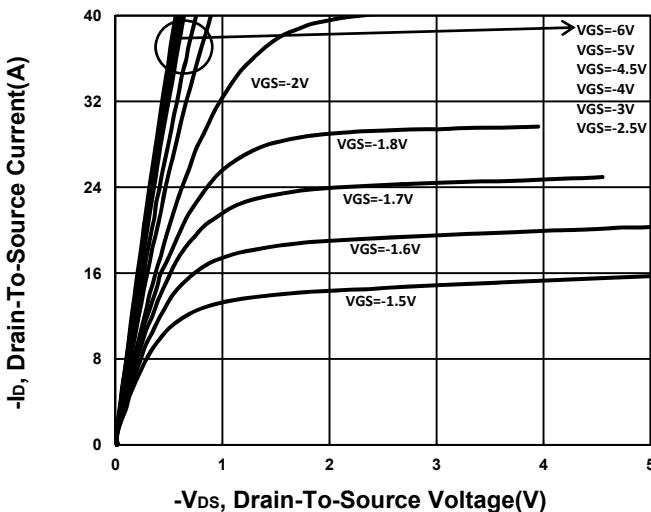
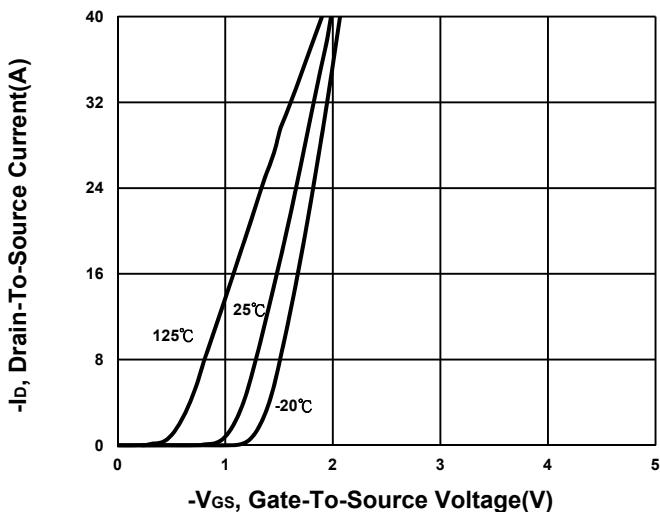
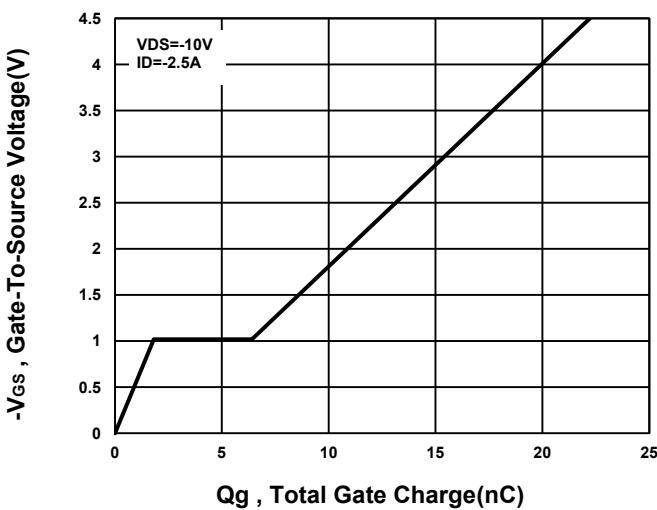
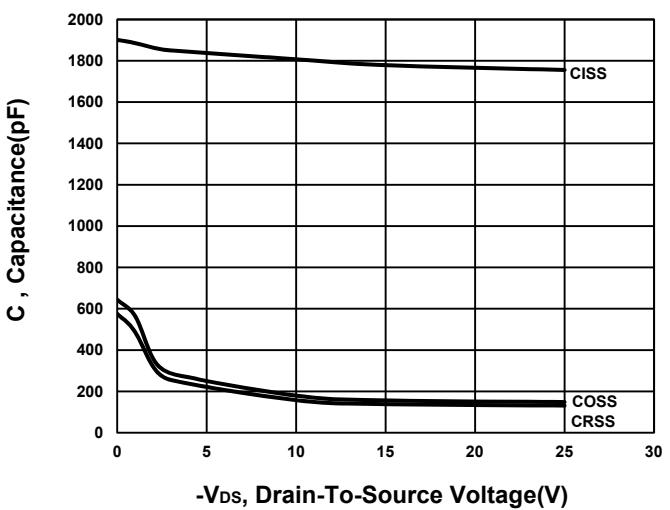
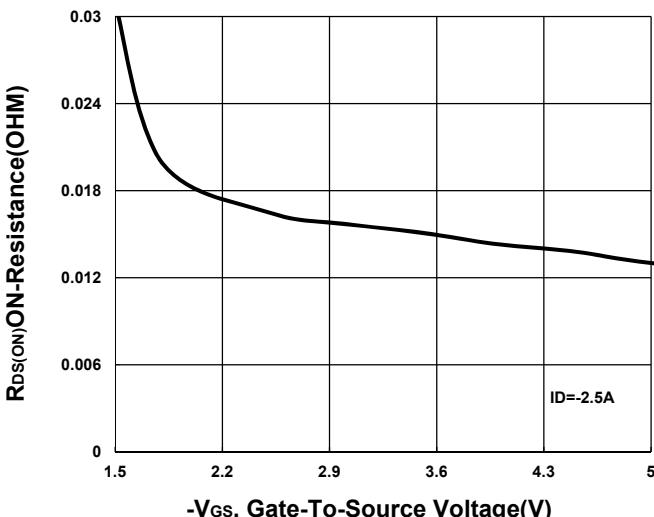
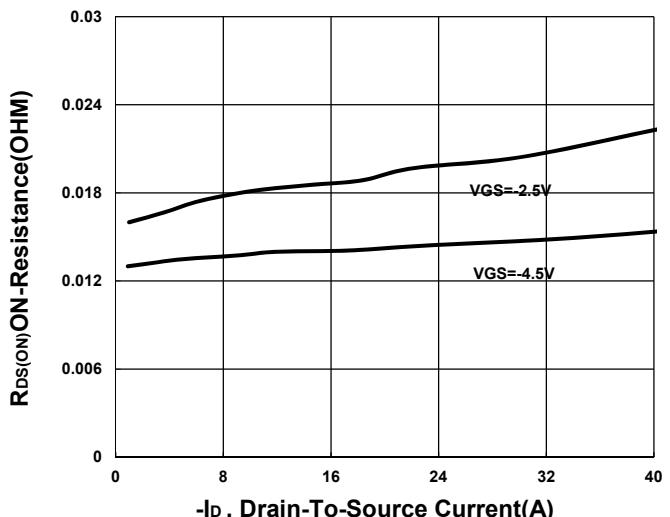
NIKO-SEM
**P-Channel Logic Level Enhancement Mode
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PE521BA
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ELECTRICAL CHARACTERISTICS (T_J = 25 °C, Unless Otherwise Noted)

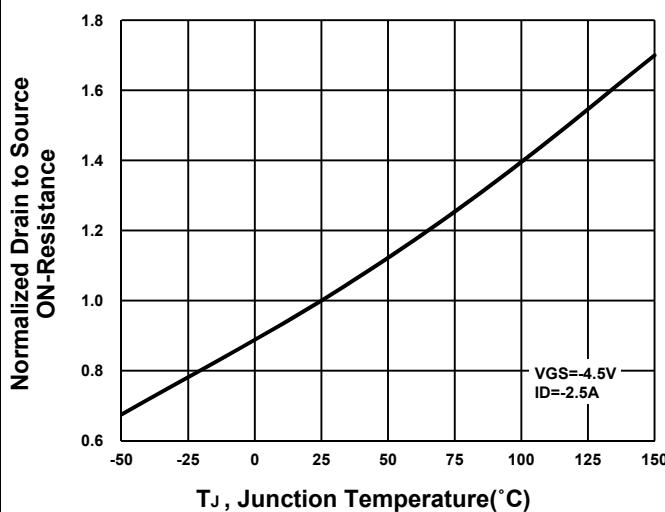
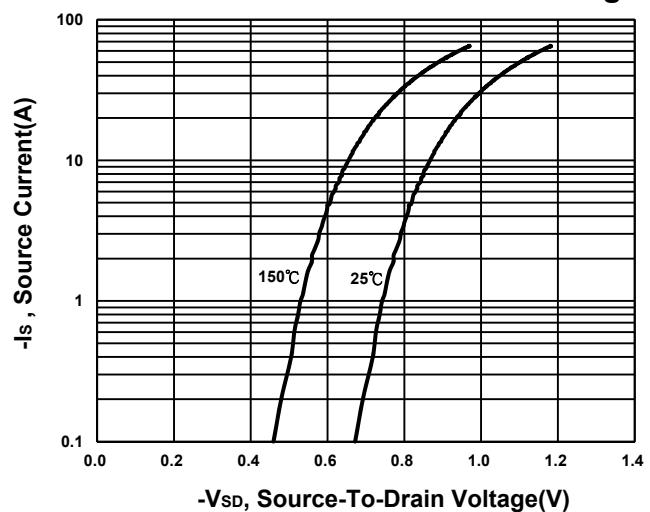
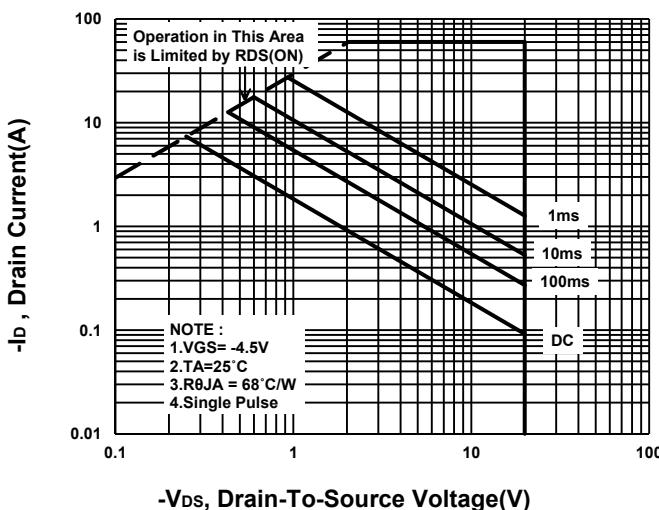
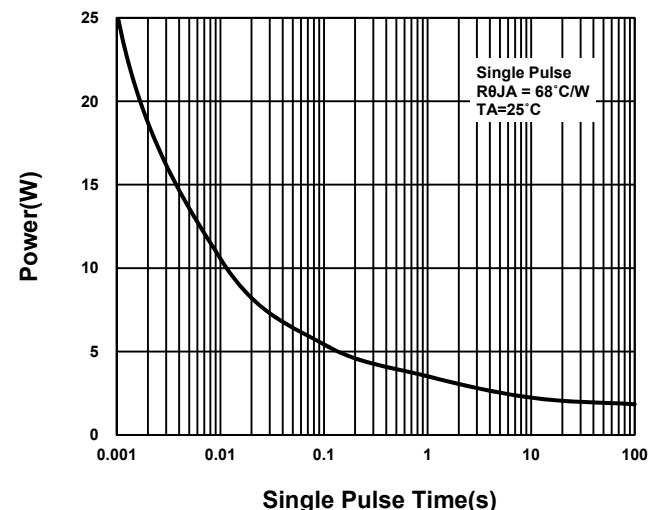
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0V, I _D = -250μA	-20			V
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = -250μA	-0.3	-0.6	-1	
Gate-Body Leakage	I _{GSS}	V _{DS} = 0V, V _{GS} = ±8V			±100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = -16V, V _{GS} = 0V			-1	
		V _{DS} = -10V, V _{GS} = 0V, T _J = 125 °C			-10	uA
Drain-Source On-State Resistance ¹	R _{DS(ON)}	V _{GS} = -4.5V, I _D = -2.5A		14	20	
		V _{GS} = -2.5V, I _D = -2A		17	25	mΩ
		V _{GS} = -1.8V, I _D = -1A		22	35	
Forward Transconductance ¹	g _f	V _{DS} = -5V, I _D = -2.5A		21		S
DYNAMIC						
Input Capacitance	C _{iss}	V _{GS} = 0V, V _{DS} = -10V, f = 1MHz		1801		
Output Capacitance	C _{oss}			179		
Reverse Transfer Capacitance	C _{rss}			160		pF
Gate Resistance	R _g	V _{GS} = 0V, V _{DS} = 0V, f = 1MHz		10		Ω
Total Gate Charge ²	Q _{g(VGS=-4.5V)}	V _{DS} = -10V, I _D = -2.5A		22.7		
	Q _{g(VGS=-2.5V)}			13.3		
Gate-Source Charge ²	Q _{gs}			1.9		nC
Gate-Drain Charge ²	Q _{gd}			5.4		
Turn-On Delay Time ²	t _{d(on)}	V _{DS} = -10V, I _D ≈ -2.5A, V _{GS} = -4.5V, R _{GS} = 6Ω		19		
Rise Time ²	t _r			34		
Turn-Off Delay Time ²	t _{d(off)}			216		
Fall Time ²	t _f			165		nS
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T_J = 25 °C)						
Continuous Current ³	I _s				-16	A
Forward Voltage ¹	V _{SD}	I _F = -2.5A, V _{GS} = 0V			-1.2	V
Reverse Recovery Time	t _{rr}	I _F = -2.5A , dl _F /dt = 100 A / μS		35		nS
Reverse Recovery Charge	Q _{rr}			18		nC

¹Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.

²Independent of operating temperature.

³Package limitation current is -11A.

NIKO-SEM**P-Channel Logic Level Enhancement Mode
Field Effect Transistor****PE521BA
PDFN 3x3P
Halogen-Free & Lead-Free****Output Characteristics****Transfer Characteristics****Gate charge Characteristics****Capacitance Characteristic****On-Resistance VS Gate-To-Source****On-Resistance VS Drain Current**

NIKO-SEM**P-Channel Logic Level Enhancement Mode
Field Effect Transistor****PE521BA
PDFN 3x3P
Halogen-Free & Lead-Free****On-Resistance VS Temperature****Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**